Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/017 05/	

10/817,251 Examiner

Huyen Le

WILEY, LIEN L.

3751

SEARCHED					
Class	Subclass	Date	Examiner		
401	21 208	4/14/2006	HL		
	210 216				
	219 220				
	263 270				
	281 204				
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INTERFERENCE SEARCHED					
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